

[54] AUTOMATIC PERIMETER FOR EYESIGHT EXAMINATION

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[**] Term: 14 Years

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[30] Foreign Application Priority Data

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[52] U.S. Cl. D24/17

[58] Field of Search D24/17; 351/226; D16/2

[56] References Cited

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[57] CLAIM

The ornamental design for an automatic perimeter for eyesight examination, as shown and described.

DESCRIPTION

FIG. 1 is a front elevational view of an automatic perimeter for eyesight examination showing our new design.

FIG. 2 is a rear elevational view thereof.

FIG. 3 is a side elevational view thereof as viewed from the left side of FIG. 1.

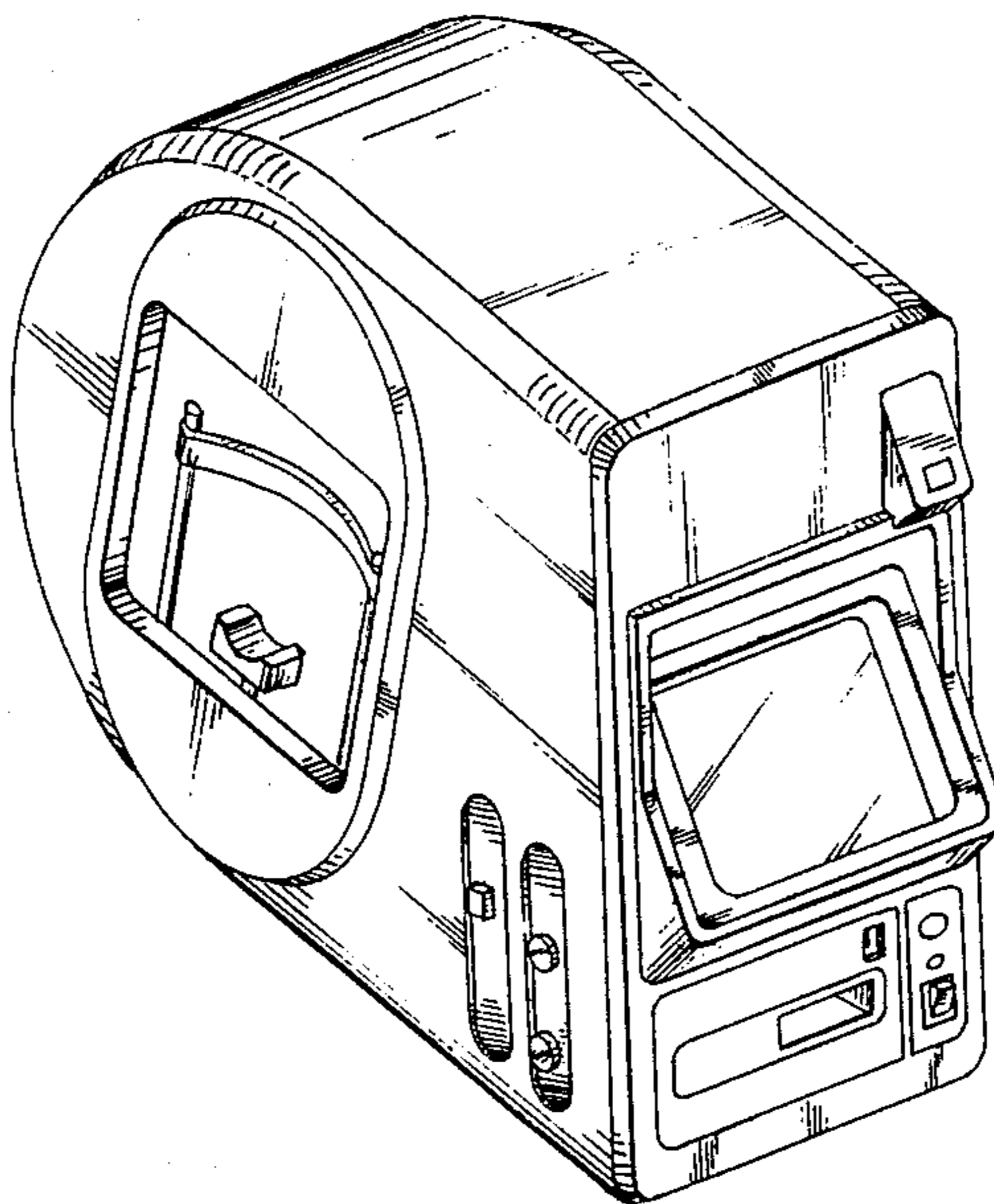
FIG. 4 is a side elevational view thereof as viewed from the right side of FIG. 1.

FIG. 5 is a top plan view thereof.

FIG. 6 is a bottom plan view thereof and,

FIG. 7 is a sectional view thereof taken along the line 7—7 of FIG. 3.

FIG. 8 is a front perspective view thereof.



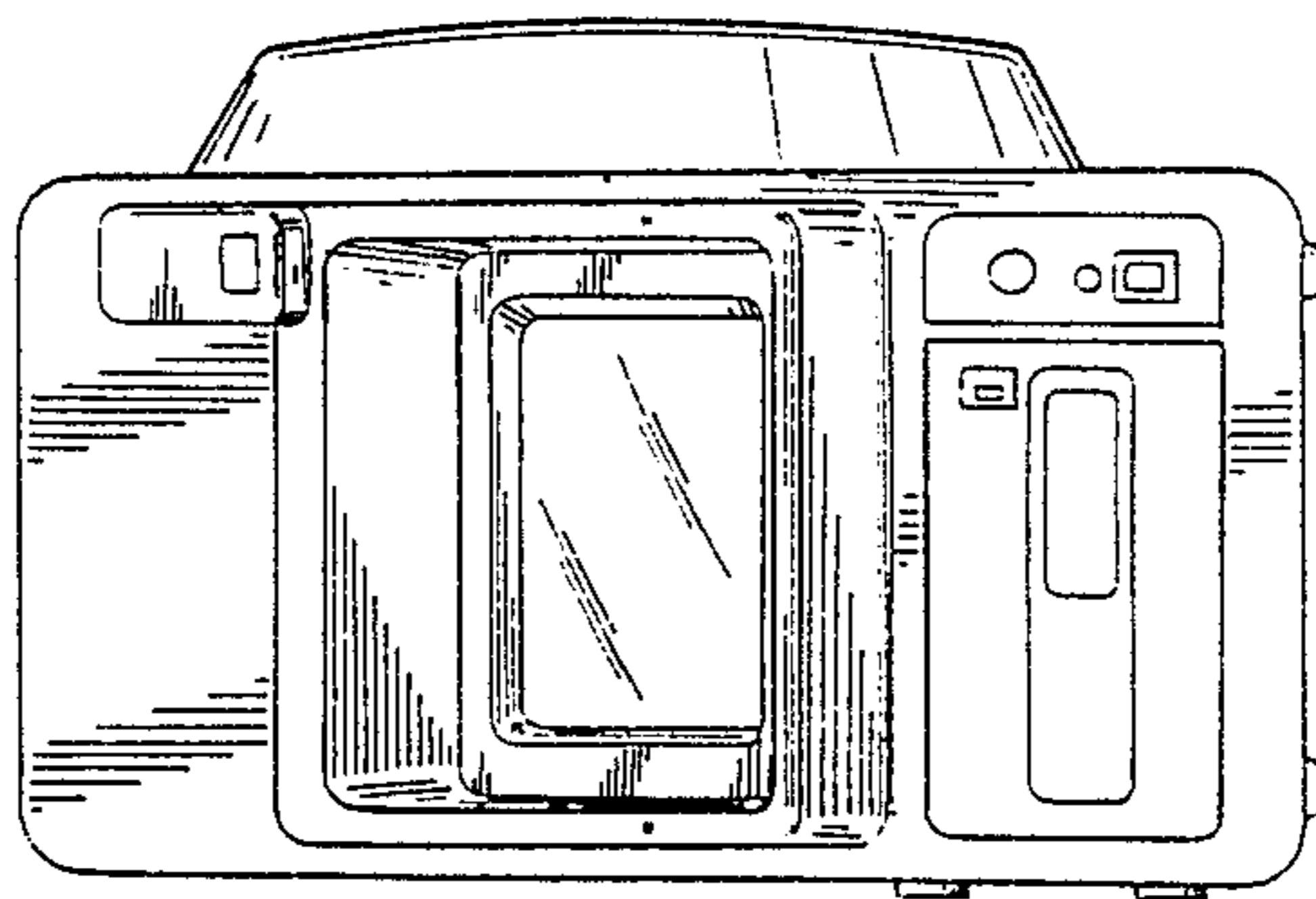


FIG. 1

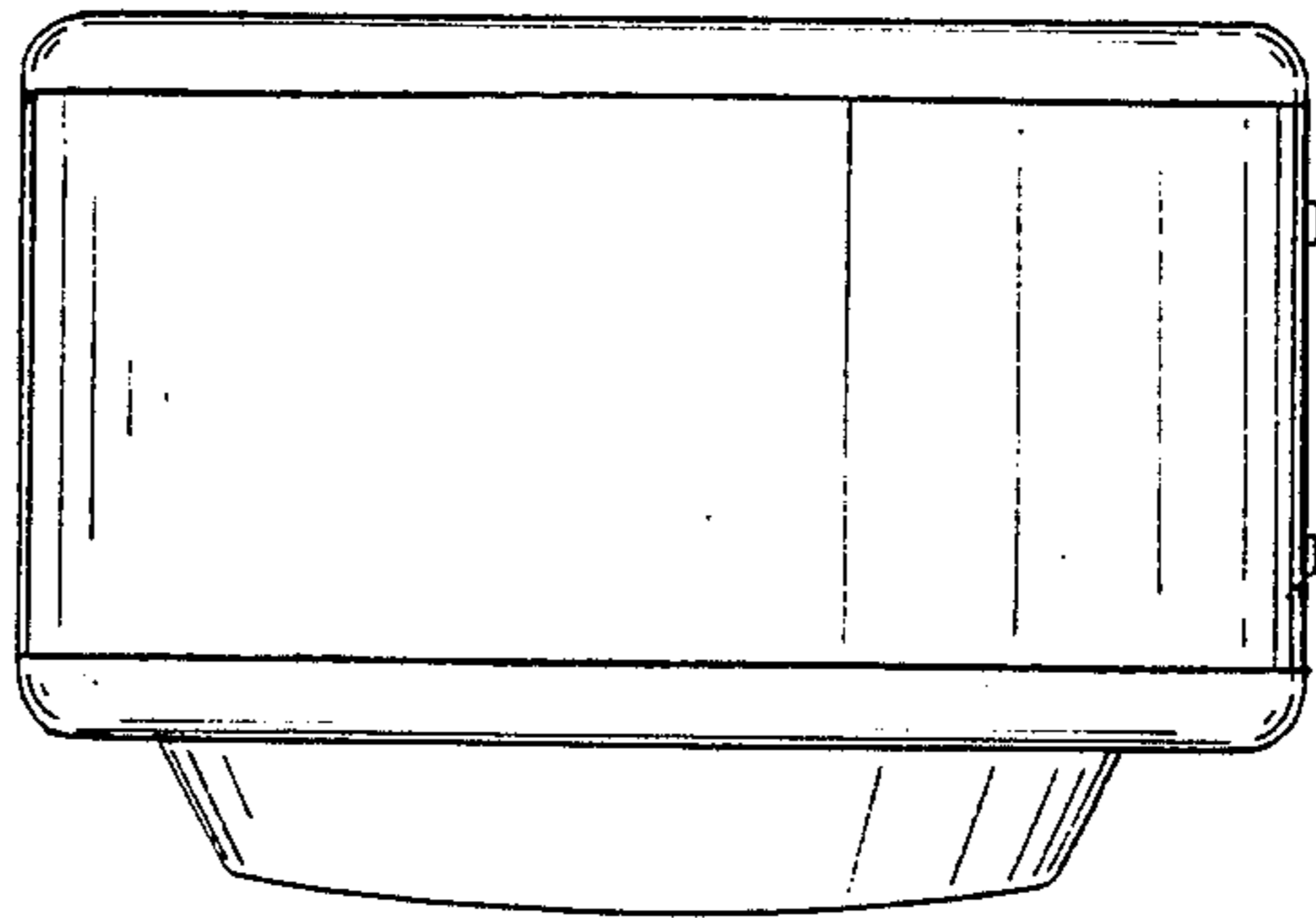


FIG. 2

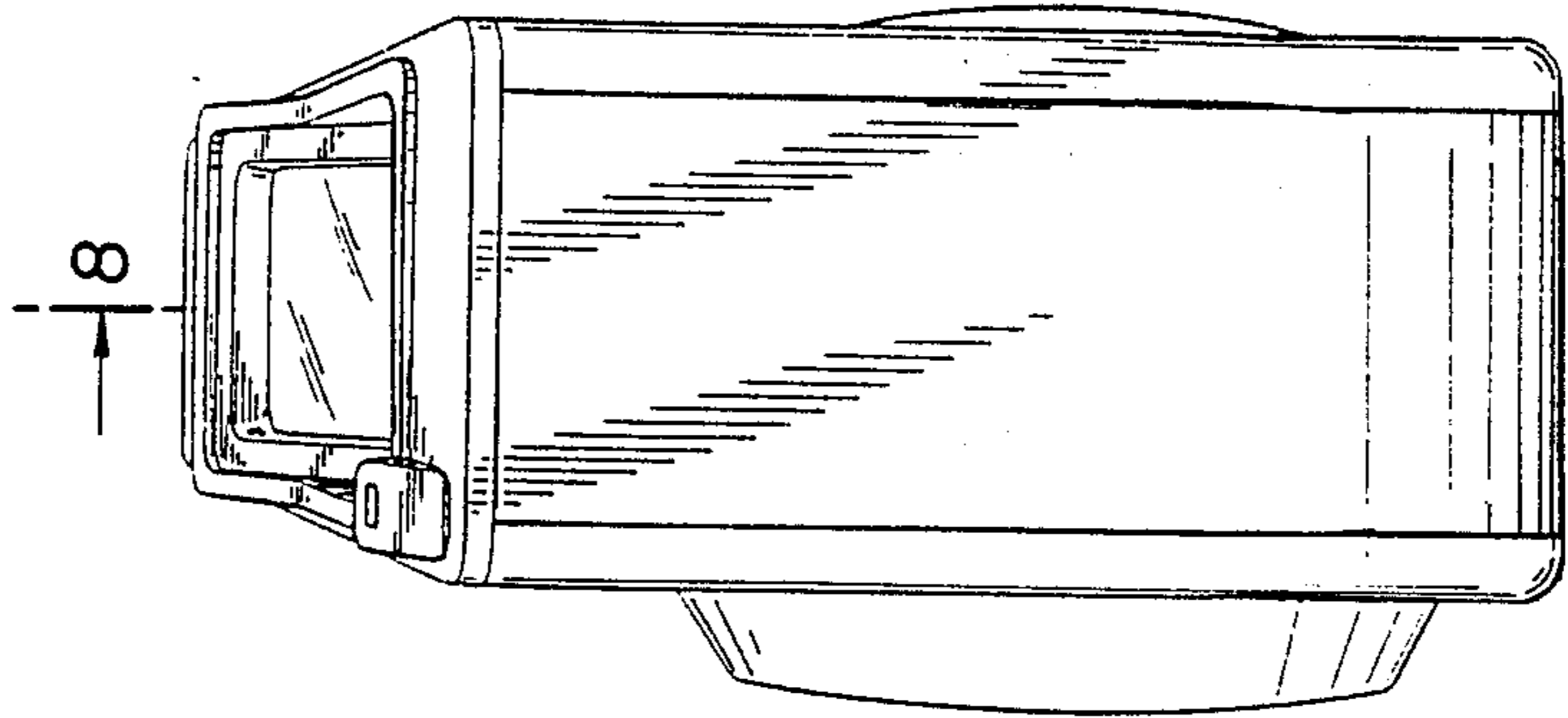


FIG. 5

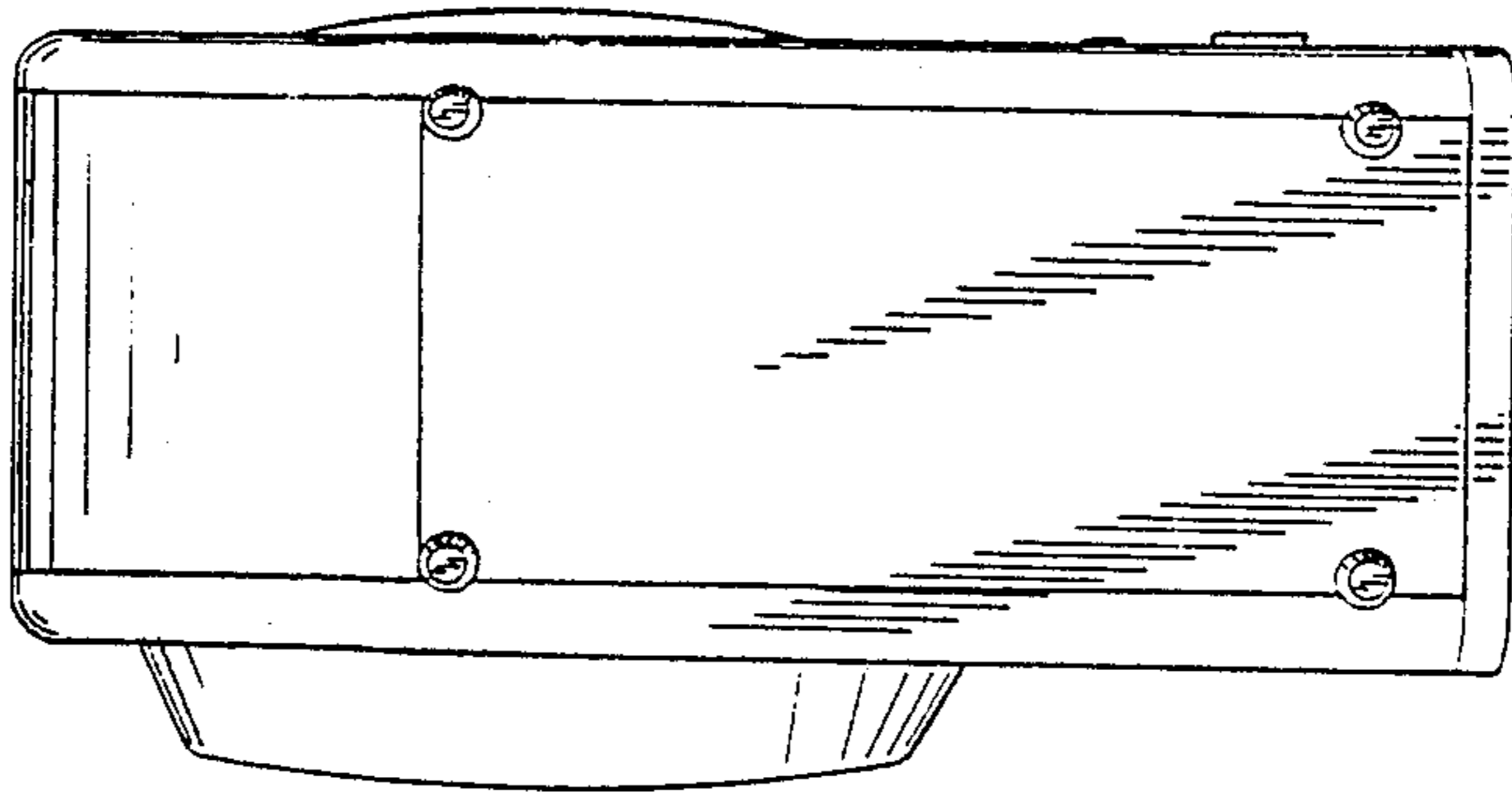


FIG. 6

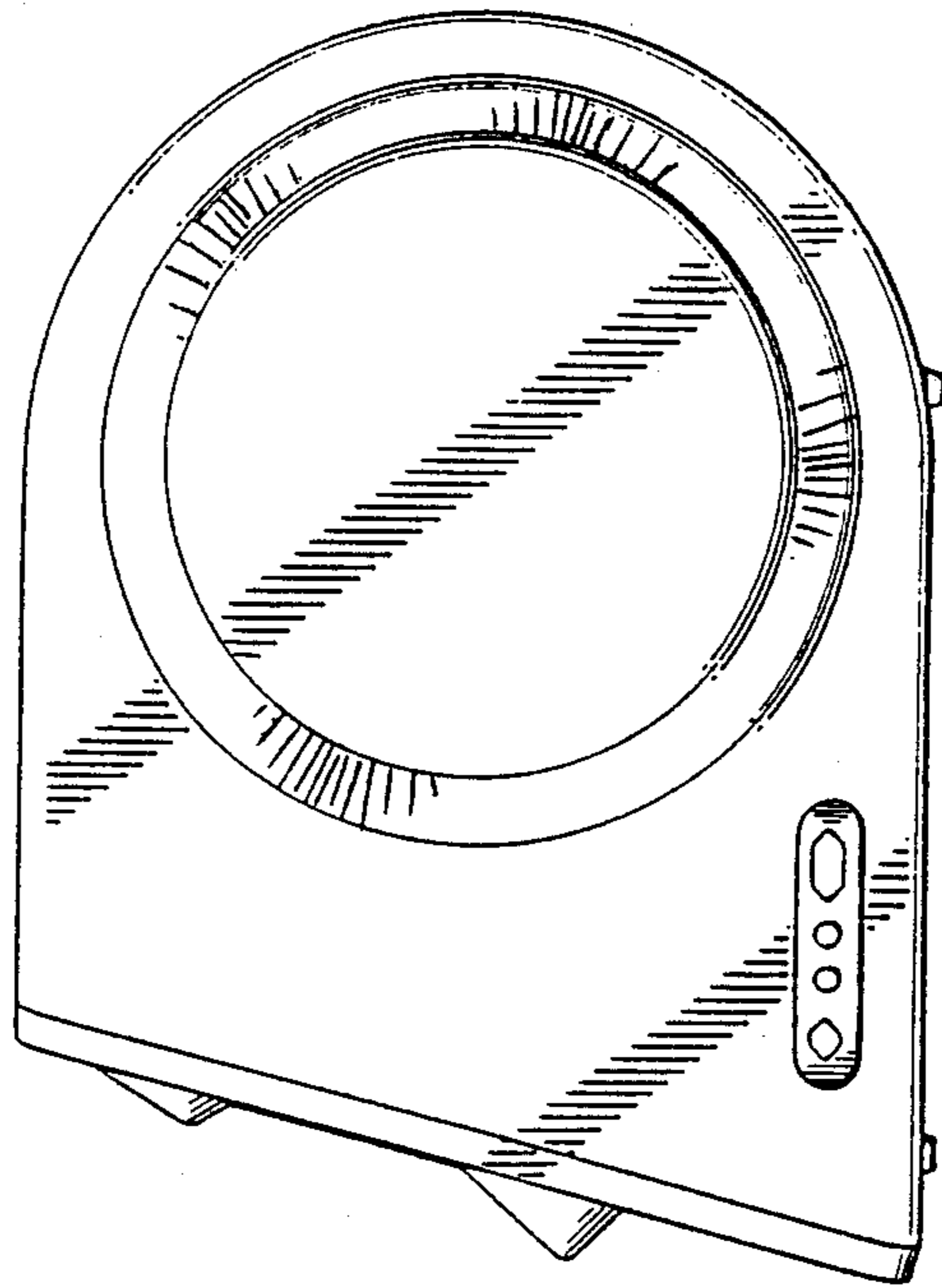


FIG. 4

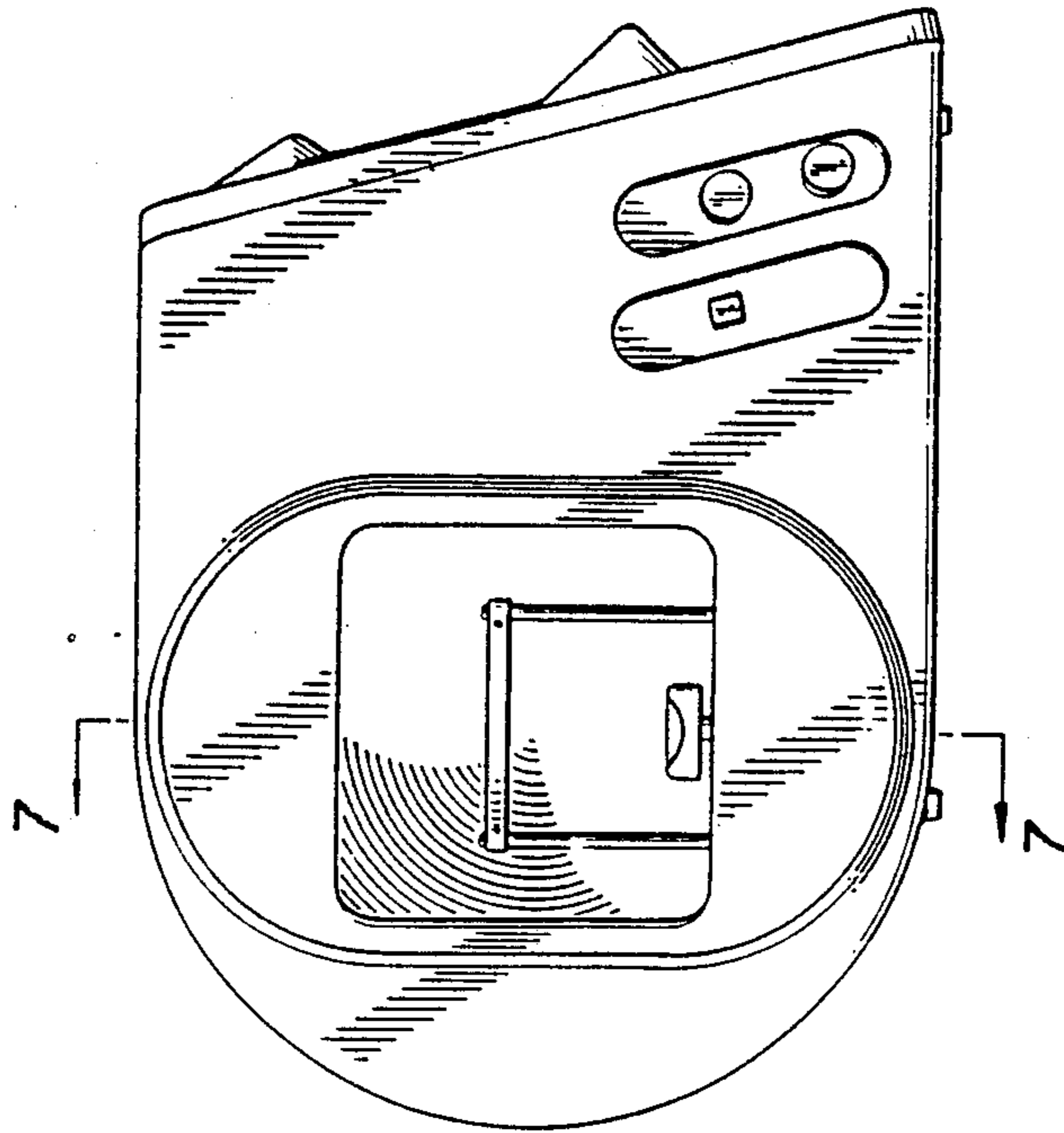
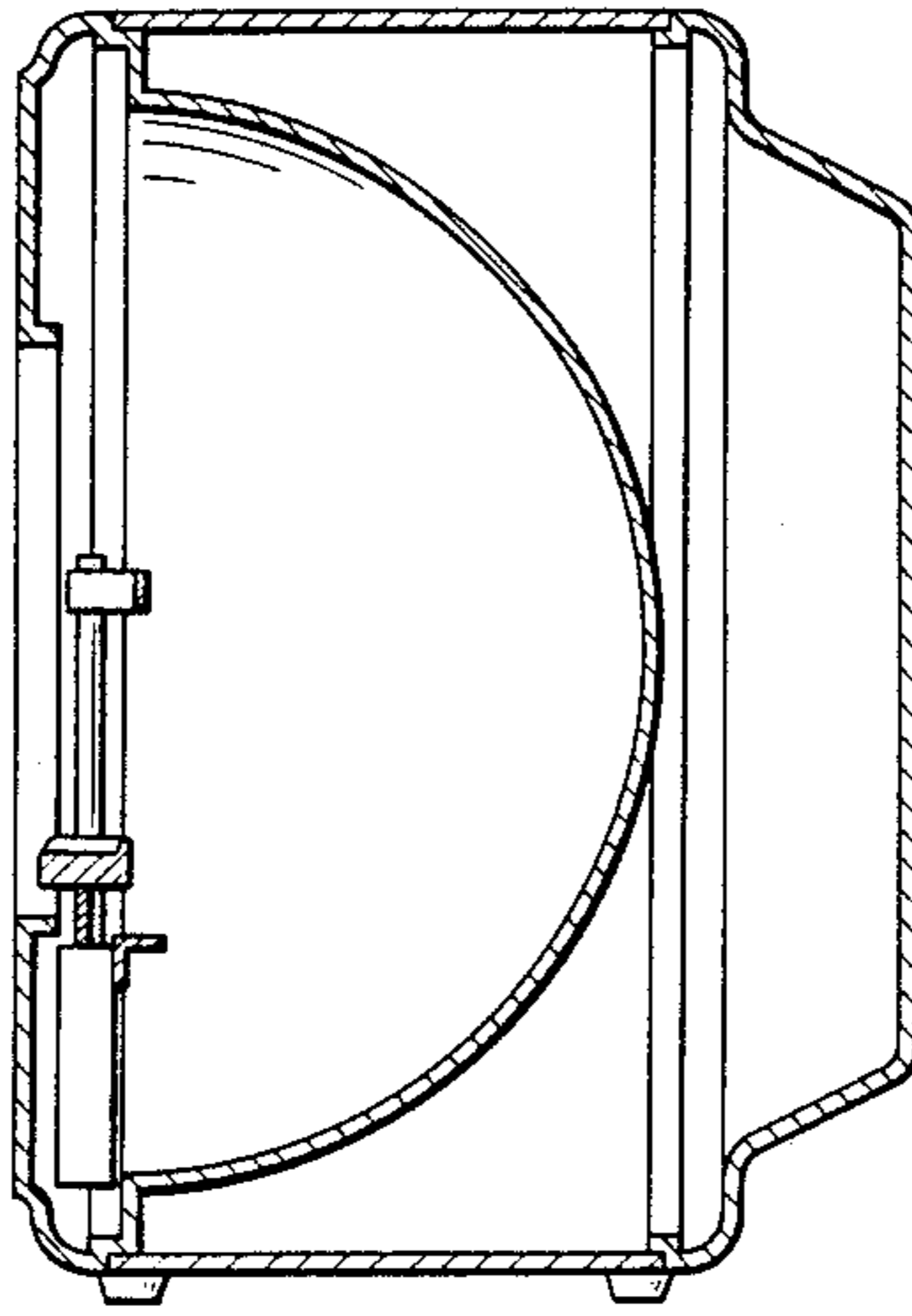


FIG. 3

FIG. 7



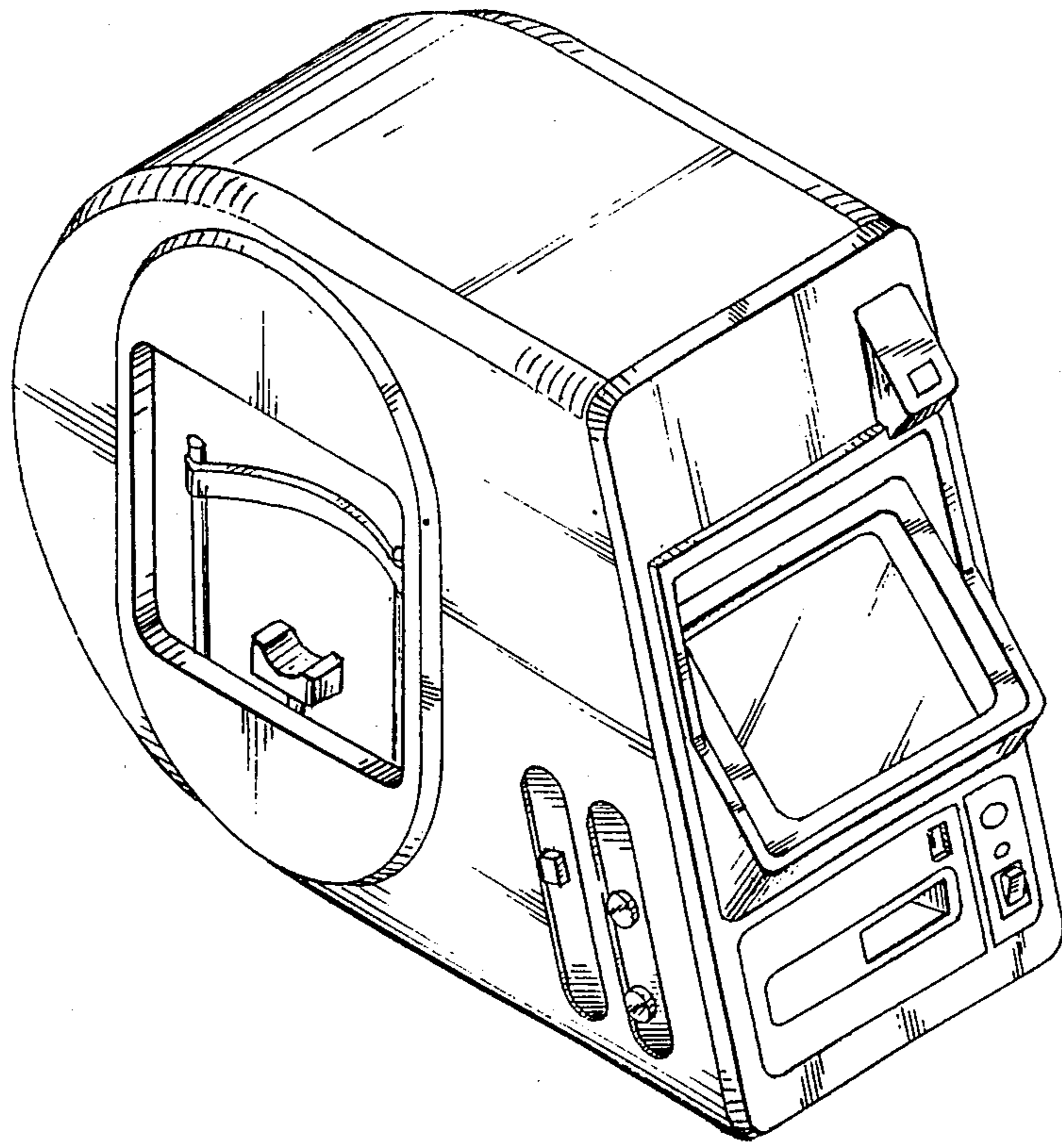


FIG. 8